Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/621,020	TENCA ET AL.		
Examiner	Art Unit		
Christopher A. Revak	2131		

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	8/25/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	8/25/2005	CR
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